Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

AHN, KEUN HEE

Art Unit

Jacob Meek

09/934,693

Examiner

2637

SEARCHED				
Class	Subclass	Date	Examiner	
375	326,341 340,348 230,232 344	6/24/2005	JM	
329	304,306	6/24/2005	JM	
375	344,216	6/24/2005	JM	
375	321	6/24/2005	JM	
331	4	6/24/2005	JM	
375	329,331	6/24/2005	JM	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	316	6/24/2005	JM	
375	229	6/24/2005	JM	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East	6/24/2005	ML		
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